P28646.A01

LT3 Rec'd PCT/PTO 12 JAN 2006 P

Group Art Unit: Not Yet Assigned

IN THE UNITED STATESPATENT AND TRADEMARK OFFICE

Applicants

: Hiroshi SUDA et al JAN 1.2 7006

Appl. No.

: 10/552,743

(U.S. National Stage of PC1/JP2004/007593)

I.A. Filed

: May 26, 2004

Examiner: Not Yet Assigned

For

: CHARGED FINE PARTCULATE WATE, AND METHOD OF

CREATING ENVIRONMENT WHERE MIST OF THE CHARGED

FINE PARTICULATE WATER IS DISPERSED

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
U.S. Patent and Trademark Office
Customer Service Window, Mail Stop AMENDMENT
Randolph Building
401 Dulany Street
Alexandria, VA 22314

RECEIVED OIPE/IAP

JAN 2 3 2006

Sir:

In accordance with the duty of disclosure under 37 C.F.R. § 1.56 and §§1.97-1.98, Applicant hereby brings the following information to the attention of the Examiner in charge of the above-identified application, which includes information cited and discussed in the specification and the International Search Report issued in connection with International Patent Application No.

PCT/JP2004/007593, of which the present application is the U.S. National Stage Application. Copies of the International Search Report and the International Preliminary Examination Report were enclosed with the papers when entering the U.S. National Stage on October 12, 2005. The Examiner is invited to review these materials to inspect the relevance indicated during international

examination with respect to the documents cited therein. The following is a list of the documents cited in the above-noted documents:

Japanese Laid-open Patent Publication No. 2001-170514, together with an English language machine translation of the same. Applicants note that this document is cited on page 1 of the specification of the present application;

Japanese Laid-open Patent Publication No. 62-144744, together with an English language abstract of the same;

Japanese Laid-open Patent Publication No. 2002-203657, together with an English language machine translation of the same;

Japanese Laid-open Patent Publication No. 2001-96190, together with an English language machine translation of the same. Applicants note that this document is cited on page 1 of the specification of the present application;

Japanese Laid-open Patent Publication No. SHO 53-141167, together with an English language abstract of the same. Applicants note that this document is cited on page 1 of the specification of the present application;

Japanese Laid-open Patent Publication No. 2003-79714, together with an English language machine translation of the same;

Japanese Patent No. 3260150, together with patent family member U.S. Patent No. 5,337,693; and

Japanese Laid-open Patent Publication No. 2003-14261, together with an English language machine translation of the same.

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Further to 37 C.F.R. §1.98 (a)(2)(ii), a copy of the U.S. patent is not enclosed herewith. However, if a copy is needed, the Examiner is respectfully requested to contact the undersigned.

Applicants respectfully request that the Examiner consider the above material and cite the same. Copies of the above-noted foreign documents are attached hereto and all of the above-noted documents are listed on the attached PTO-1449 Form. The Examiner is requested to initial the appropriate spaces on the attached Form and to return a copy of the completed Form to Applicants with the next official communication in the present application.

In accordance with 37 C.F.R. § 1.97(b)(1), this Information Disclosure Statement is filed within three months of the filing date of the application.

Accordingly, no fees are required.

Should the Examiner have any questions, the Examiner is invited to contact the undersigned at the below-listed telephone number.

Respectfully Submitted, Hiroshi SUDA et al.

Bruce H. Bernstein

Reg. No. 29,027

Stephen M. Roylance Reg. No. 31,296

January 12, 2006 GREENBLUM & BERNSTEIN, P.L.C. 1950 Roland Clarke Place] Reston, VA 20191 (703) 716-1191

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	1 7	English Language Abstract of JP 2001-170514.
	2	English Language Abstract of JP 62-144744.
	3	English Language Abstract of JP 2002-203657.
	4	English Language Abstract of JP2001-96190.
	5	English Language Abstract of JP53-141167
	6	English Language Abstract of JP 2003-79714.
	7	English Language Abstract of JP 2003-14261.

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.